

# Search Notes



Application/Control No.

10/774,788

Examiner

Patrick J. Lee

Applicant(s)/Patent under  
Reexamination

SHIN ET AL.

Art Unit

2878

## SEARCHED

Class	Subclass	Date	Examiner
250	227.14, 227.16, 227.18, 227.23	5/18/05 5/19/05	PL
385	12-13		PL
385	31-32		PL
385	37		PL
356	32, 35.5		PL
356	73.1		PL

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Consulted w/ S. Allen	5/17/2005	PL
East (See attached)	5/18/2005	PL
East (See attached)	5/19/2005	PL